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- Inputs Are TTL-Voltage Compatible
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

#### description

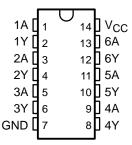
The 'HCT14 contain six independent inverters. The devices perform the Boolean function  $Y = \overline{A}$  in positive logic.

The SN54HCT14 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HCT14 is characterized for operation from –40°C to 85°C.

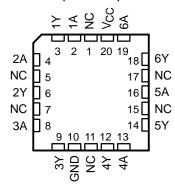
FUNCTION TABLE (each inverter)

INPUT A	OUTPUT Y
Н	L
L	Н

#### SN54HCT14 . . . J OR W PACKAGE SN74HCT14 . . . D, DB, N, OR PW PACKAGE (TOP VIEW)

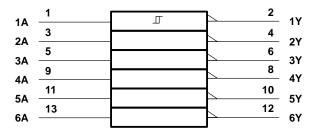


### SN54HCT14 . . . FK PACKAGE (TOP VIEW)



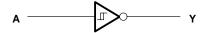
NC - No internal connection

#### logic symbol†



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, J, N, PW, and W packages.

#### logic diagram (positive logic)





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



#### SN54HCT14, SN74HCT14 HEX SCHMITT-TRIGGER INVERTERS

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#### absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V <sub>CC</sub>		0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)		. $-0.5$ V to V <sub>CC</sub> +0.5 V
Output voltage range, VO (see Note 1)		. $-0.5$ V to V <sub>CC</sub> +0.5 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )		±20 mA
Output clamp current, IOK (VO < 0 or VO > VCO	c)	±20 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	- 	±25 mA
Continuous current through V <sub>CC</sub> or GND		±50 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2):	: D package	127°C/W
	DB package	158°C/W
	N package	78°C/W
	PW package	170°C/W
Storage temperature range, T <sub>stg</sub>		–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

#### recommended operating conditions

				ICT14	SN74F	UNIT	
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage		4.5	5.5	4.5	5.5	V
$V_{IH}$	High-level input voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	2.1		2.1		V
V <sub>IL</sub>	Low-level input voltage	V <sub>CC</sub> = 4.5 V to 5.5 V		0.5		0.5	V
٧ <sub>I</sub>	V <sub>I</sub> Input voltage		0	VCC	0	VCC	V
VO Output voltage		0	VCC	0	VCC	V	
TA	T <sub>A</sub> Operating free-air temperature			125	-40	85	°C



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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V	T <sub>A</sub> = 25°C			SN54HCT14		SN74HCT14		UNIT
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
V <sub>T+</sub>		4.5 V	1.2	1.5	1.9	1.2	1.9	1.2	1.9	V
Positive-going threshold		5.5 V	1.4	1.7	2.1	1.4	2.1	1.4	2.1	V
V <sub>T</sub> _ Negative-going		4.5 V	0.5	0.9	1.2	0.5	1.2	0.5	1.2	V
threshold		5.5 V	0.6	1	1.4	0.6	1.4	0.6	1.4	
ΔV <sub>T</sub> Hysteresis		4.5 V	0.4	0.6	1.4	0.4	1.4	0.4	1.4	V
(V <sub>T+</sub> – V <sub>T</sub> –)		5.5 V	0.4	0.65	1.5	0.4	1.5	0.4	1.5	V
VOH	$V_I = V_{IH}$ or $V_{IL}$ , $I_{OH} = -20 \mu A$	4.5 V	4.4	4.49		4.4		4.4		
VOH	$V_I = V_{IH}$ or $V_{IL}$ , $I_{OH} = -4$ mA	4.5 V	3.98	4.3		3.7		3.84		
Val	$V_I = V_{IH}$ or $V_{IL}$ , $I_{OL} = 20 \mu A$	4.5 V		0.001	0.1		0.1		0.1	V
VOL	$V_I = V_{IH}$ or $V_{IL}$ , $I_{OL} = 4$ mA	4.5 V		0.17	0.26		0.4		0.33	V
lį	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			±0.1		±1		±1	μΑ
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			2		40		20	μΑ
ΔI <sub>CC</sub> †	One input at 0.5 V or 2.4 V, Other inputs at GND or V <sub>CC</sub>	5.5 V		0.2	2.4		3		2.9	mA
C <sub>i</sub>	VI = V <sub>CC</sub> or GND	5 V		3	10		10		10	pF

<sup>†</sup> This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V<sub>CC</sub>.

# switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

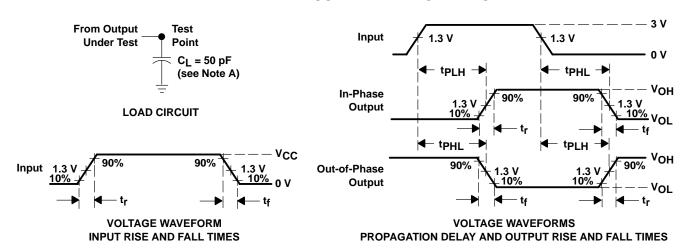
PARAMETER FROM TO	V	T,	<b>Վ = 25°</b> C	;	SN54H	ICT14	SN74H	ICT14	UNIT		
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
<b>.</b>	Δ.	Υ	4.5 V		20	32		48		40	20
<sup>t</sup> pd	A		5.5 V		18	30		45		38	ns
		V	4.5 V		7	15		22		19	
ч	ч   т	5.5 V		6	14		20		17	ns	

#### operating characteristics, T<sub>A</sub> = 25°C

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance	No load	10	pF

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#### PARAMETER MEASUREMENT INFORMATION



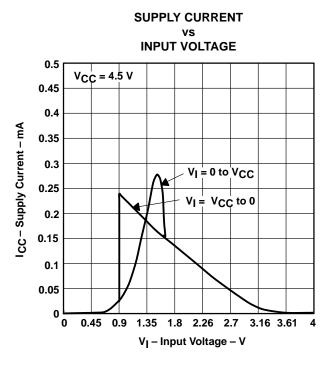
NOTES: A.  $C_L$  includes probe and test-fixture capacitance.

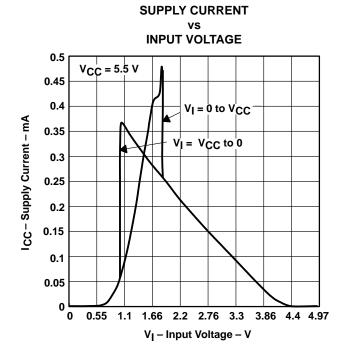
- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_{\Omega} = 50 \Omega$ ,  $t_{r} = 6 \text{ ns}$ ,  $t_{f} = 6 \text{ ns}$ .
- C. The outputs are measured one at a time with one input transition per measurement.
- D. tpLH and tpHL are the same as tpd.

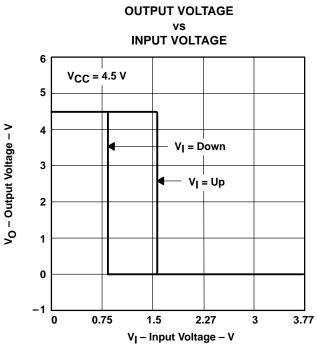
Figure 1. Load Circuit and Voltage Waveforms

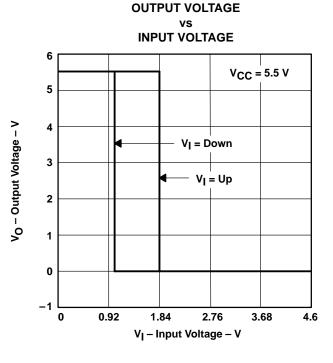


#### TYPICAL CHARACTERISTICS









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